

Mapping physical defects to logic level for defect oriented testing

Ubar, Raimund-Johannes SCS 2003 : International Symposium on Signals, Circuits and Systems : July 10-11, 2003, Iasi, Romania
: proceedings. Vol. 2 2003 / p. 453-456 : ill <https://ieeexplore.ieee.org/document/5731320>